

# FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #20056A

Generic Copy

Issue Date: 05-Apr-2013

**TITLE:** VHVIC 2nd Source Qualification to Gresham FAB – Phase 5

PROPOSED FIRST SHIP DATE: 05-Jul-2013

AFFECTED CHANGE CATEGORY(S): Wafer FAB location

#### FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:

Contact your local ON Semiconductor Sales Office or <Scott.Brow@onsemi.com>

**SAMPLES:** Contact your local ON Semiconductor Sales Office

#### **ADDITIONAL RELIABILITY DATA:** Available

Contact your local ON Semiconductor Sales Office or <Ken.Fergus@onsemi.com>

#### **NOTIFICATION TYPE:**

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 90 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact <quality@onsemi.com>.

#### **DESCRIPTION AND PURPOSE:**

The purpose of this final PCN is to notify customers of the platform qualification of a second source for the devices listed in this FPCN at ON Semiconductor's wafer fabrication facilities in Gresham, Oregon.

This qualification is being made to increase the capacity for this technology. This technology is currently produced out of ON Semiconductor's wafer fabrication facilities in Aizu, Japan

The VHVIC0 process is being duplicated at the Gresham wafer FAB. No die design changes have occurred. No changes to the device performance, data sheets or packaging have been made.

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# **RELIABILITY DATA SUMMARY:**

NCP1200D60R2G					
#	Test	Test Conditions	Read Points	Sample Size	Results
1	HTBB	TA=125C, 450V Bias	Test @ 1008hrs	3 lots x 80 units	0/240
2	HVTHB	TA=85C, 60% RH, 450V bias	Test @ 168hrs	3 lots x 80 units	0/240
3	HTOL	TA=125C, 200V Bias	Test @ 1008hrs	3 lots x 80 units	0/240
4	HTSL	TA=150C	Test @ 1008hrs	3 lots x 80 units	0/240
5	PC-TC	-65C to +150C	Test @ 500 Cycles	3 lots x 80 units	0/240
6	PC-AC	TA=121C, RH=100%, PSI=15	Test @ 96hrs	3 lots x 80 units	0/240
7	PC-UHAST	TA=130C, RH=85%, PSI=18.8 no	Test @ 96hrs	3 lots x 80 units	0/240
		Bias			

## **ELECTRICAL CHARACTERISTIC SUMMARY:**

There is no change in the electrical performance. Datasheet specifications remain unchanged.

# **CHANGED PART IDENTIFICATION:**

Affected products with date code WW14-2013 and greater may be sourced from either Gresham or Aizu wafer Fabrication site.

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## **List of affected General Parts:**

MC33364D1G

MC33364D1R2G

MC33364D2G

MC33364D2R2G

MC33364DG

MC33364DR2G

NCP1200D100R2G

NCP1200D40R2

NCP1200D60R2G

NCP1200P100G

NCP1200P40G

NCP1200P60G

NCP1230D100R2G

NCP1230D133R2G

NCP1230D165R2G

NCP1230D65R2G

NCP1230P100G

NCP1230P133G

NCP1230P65G

## **List of affected Customer Specific Parts:**

SCY99063D65R2G SCY99100D100R2G

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